

Test Report



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Report No. A2250451098104001

Company Name SEMICONDUCTOR MANUFACTURING NORTH CHINA (BEIJING) CORP.

shown on Report

Address 18 WENCHANG ROAD, BEIJING ECONOMIC-TECHNOLOGICAL
DEVELOPMENT AREA, CHINA, 100176

The following sample(s) and sample information was/were submitted and identified by/on the behalf
of the applicant

Sample Name Wafer
Model No. SMNC(BJ) Cu Process 40nm Production Wafer
Sample Received Date Jun. 30, 2025
Testing Period Jun. 30, 2025 to Jul. 3, 2025

Test Requested As specified by client, to test Antimony(Sb) in the submitted sample(s).

Test Method Please refer to the following page(s).

Test Result(s) Please refer to the following page(s).



Approved by

Chen Kaimin

Chen kaimin

Lab Manager

Date

Jul. 3, 2025

No. R268853350

No.1351, Wanfang Road, Minhang District, Shanghai, China

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Test Method

Test Item(s)	Test Method	Measured Equipment(s)
Antimony(Sb)	Refer to US EPA 3052:1996 & US EPA 6010D:2018	ICP-OES

Test Result(s)

Tested Item(s)	Result	MDL
	001	
Antimony (Sb)	N.D.	10 mg/kg

Sample/Part Description

No.	CTI Sample ID	Description
1	001	Wafer

Remark: The sample(s) had been dissolved totally tested for Antimony.

-MDL = Method Detection Limit

-N.D. = Not Detected (<MDL)

-mg/kg = ppm = parts per million

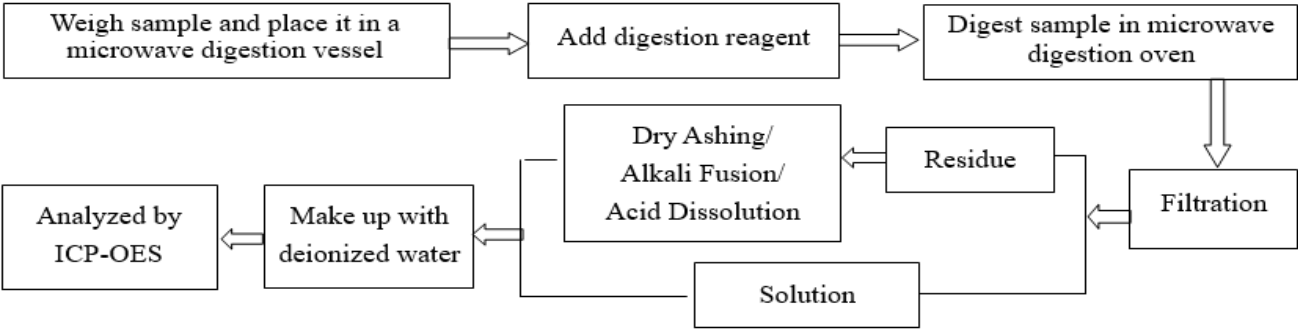
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Test Process

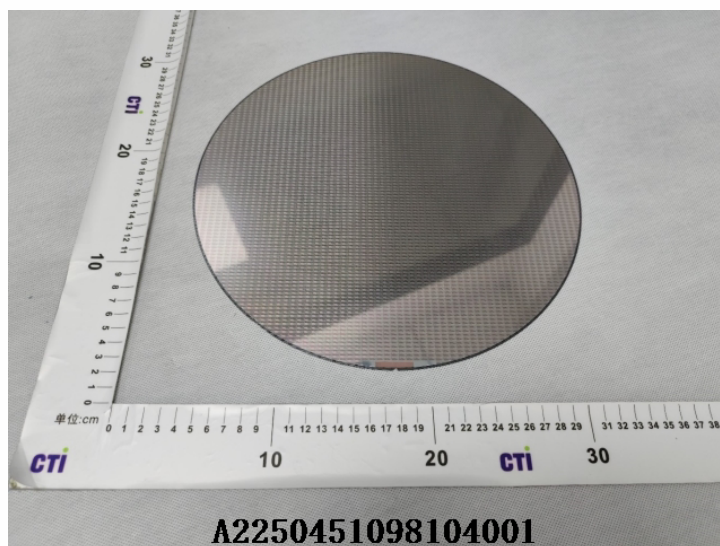


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Photo(s) of the sample(s)



Statement:

1. This report is considered invalid without approved signature, special seal and the seal on the perforation;
2. The Company Name shown on Report and Address, the sample(s) and sample information was/were provided by the applicant who should be responsible for the authenticity which CTI hasn't verified;
3. The result(s) shown in this report refer(s) only to the sample(s) tested;
4. Unless otherwise stated, the decision rule for conformity reporting is based on Binary Statement for Simple Acceptance Rule (w=0) stated in ILAC-G8:09/2019 / CNAS-GL015:2022;
5. Without written approval of CTI, this report can't be reproduced except in full;
6. In case of any discrepancy between the English version and Chinese version of the testing reports (if generated), the Chinese version shall prevail.

*** End of report ***

有限公司